

Complementary LEEM and eV-TEM for imaging and spectroscopy

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Abstract

Transmission electron microscopy at very low energy is a promising way to avoid damaging delicate biological samples with the incident electrons, a known problem in conventional transmission electron microscopy. For imaging in the 0-30 eV range, we added a second electron source to a low energy electron microscopy (LEEM) setup, enabling imaging in both transmission and reflection mode at nanometer (nm) resolution. The latter is experimentally demonstrated for free-standing graphene. Exemplary eV-TEM micrographs of gold nanoparticles suspended on graphene and of DNA origami rectangles on graphene oxide further establish the capabilities of the technique. The long and short axes of the DNA origami rectangles are discernable even after an hour of illumination with low energy electrons. In combination with recent developments in 2D membranes, allowing for versatile sample preparation, eV-TEM is paving the way to damage-free imaging of biological samples at nm resolution.

1. Introduction

Electron microscopy, in particular Transmission Electron Microscopy (TEM), has become a major tool for disciplines ranging from archaeology[1] to materials science[2] and biology[3]. Modern TEM instruments accelerate electrons to hundreds of kilo-electron volts[4], where the electron Mean Free Path (MFP) increases with energy, enabling atomic resolution[5,6]. However, at such high energies beam damage is a problem, especially in organic molecules and biological specimens. Proteins, for example, can already be altered by a single electron impact[7], so imaging at lower electron energies would be preferred. Recently, the Sub-Angstrom Low-Voltage Electron (SALVE) microscopy project[8] showed, that operating at 20 keV instead of 80 keV allows for a two orders of magnitude increase in dose when imaging fullerenes[9].

Strikingly, towards very low energies (i.e. below ~30 eV) the MFP also increases, as suggested by the so-called ‘universal’ MFP vs. energy curve[10]. This allows for high electron transmission of sufficiently thin samples, with the potential of nanometer (nm) spatial resolution with minor damage. The reason for the increase of MFP at very low energies is that fewer interaction processes, e.g.

plasmonic or excitonic, can be excited. Recently, electron microscopy techniques in this very low energy regime have been successful, with a scanning TEM instrument imaging graphene[11] and a holography type instrument imaging various microorganisms[12,13]. Here, we demonstrate the imaging capabilities of eV-TEM[14–16], a new form of TEM that illuminates the sample with a collimated beam of 0-30 eV electrons, i.e. an energy four to six orders of magnitude lower than conventional TEM.

2. eV-TEM setup

To acquire TEM micrographs at low energies, we have modified an Aberration-Corrected Low-Energy Electron Microscope (AC-LEEM) by placing a miniature electron gun (0-100 eV)[14] behind the sample (see Fig. 1a). Electrons emitted from the TEM-gun illuminate the sample along the optical axis in a collimated beam (green). Transmitted electrons follow the same optical path (red) as electrons from the cold field emission LEEM gun (black) upon reflection. Thus, images of the same area can be obtained by reflected (LEEM) and transmitted (eV-TEM) electrons, by utilizing either electron source.

Figure 5: Rectangular DNA origami patches on top of mono- and double-layer graphene oxide suspended over lacey carbon web. LEEM (a) and eV-TEM (c) image of DNA origami on graphene oxide (different areas). The DNA origami is bright in LEEM and dark in eV-TEM. Intensity profiles (b, d) of the rectangular (70 nm by 90 nm) DNA origami show that the short and long axes are distinguishable. In eV-TEM, the DNA origami is partially electron transparent.

5.2 DNA origami on graphene oxide

To demonstrate the applicability of eV-TEM to biological samples, we imaged rectangular DNA origami molecules (Gattaquant Gatta-AFM nanorulers, <http://www.gattaquant.com/products/gatta-afm.html>). We deposit an aqueous solution with DNA on graphene oxide and let it dry, as graphene oxide is hydrophilic and DNA origami can self-assemble on it. The sample was stored in the microscope load-lock vacuum chamber (pressure in range of 10^{-8} mbar) for one week to allow outgassing of residues, as adsorbed water on the hydrophilic surface prevents imaging with low energy electrons (note that heating would disintegrate the DNA).

The DNA origami patches appear as dark spots in the eV-TEM micrograph (Fig. 5c, 2.0 eV). The lacey carbon support is non-transparent to electrons, just like the SiN grids, whereas the graphene oxide covers the hole with two patches of different layer-count. In LEEM (Fig. 5a, 3.0 eV) the small DNA origami patches show up brighter than the graphene oxide.

In both modes we analyze line profiles across DNA origami patches, along the short and long axis of the feature. In the line profiles (colors in Fig. 5b correspond to lines in Fig. 5a, and in Fig. 5d to Fig. 5c) the short and long axis of each rectangle can be clearly discerned. The sizes lie in the expected range of 70 nm and 90 nm, respectively.

The eV-TEM micrograph (Fig. 5c) was acquired after illuminating the sample with low energy electrons for one hour at ~ 3 eV, corresponding to a dose of $\sim 3 \cdot 10^{10}$ electrons per DNA patch. Our findings show that organic samples of tens of nm in size are observable in eV-TEM, without apparent radiation damage over a prolonged time.

6. Discussion

We have presented transmission micrographs of Au NPs and DNA origami, acquired at electron energies below 10 eV instead of tens to hundreds of keV as in conventional TEM. Thereby, eV-TEM circumvents the problem of electron beam damage to organic and biological samples to a large extent. As eV-TEM is an extension to the standard LEEM setup, we can readily switch between reflection and transmission images of the same area. Sample preparation does not require staining, as shown by depositing objects from solution on graphene and graphene oxide. Furthermore, we have examined the transmission and reflection spectra of few-layer graphene in the 0 to 75 eV energy range. Similar to many other materials ('universal' curve), the transmissivity increases at energies below the MFP minimum at about 30 eV. The characteristic oscillations in the spectra that we attribute to interference of the electron waves is not predicted by the 'universal' MFP curve. Further experiments will show if these oscillations generalize to other multilayer materials as expected for a simple interference phenomenon. It is noteworthy that similar oscillations have also been observed for

hBN using LEEM[23]. In addition to their high transmissivity, few-layer van der Waals materials are especially suitable as substrates because they are thin and flat, causing minimal deflection of the transmitted electrons. Below ~28 eV there are no first (or higher) order diffraction beams inside the graphene lattice, so there is only the directly transmitted electron beam, which simplifies analysis of the results. eV-TEM is capable of imaging structures of tens of nm in size, with a resolution better than 10 nm as determined on graphene. The resolution is currently limited by the comparably large energy spread and low spatial coherence of the electron emitter, among other factors. We expect that upgrades to the electron gun will significantly improve the quality of the images, as both electron energy spread and emission area can be dramatically reduced by laser-excited photoemission from a low workfunction transparent cathode.

Thus, eV-TEM provides new opportunities for damage-free imaging in transmission electron microscopy. As it operates in a very different energy range than conventional TEM, we expect new insights into biological matter such as proteins, DNA or cell membranes from eV-TEM. As realization of eV-TEM imaging capabilities requires only very modest modification of the sample holder and electronics, LEEM/PEEM instruments already in operation around the world can adopt this new technology at low cost.

Acknowledgments

We thank Johannes Jobst for his scientific and technological input, Kirsten Martens for help with the preparation of the DNA origami, Marcel Hesselberth and Douwe Scholma for their excellent technical support and Ruud van Egmond for building the eV-TEM gun assembly. This work was supported by the Netherlands Organization for Scientific Research (NWO) via the STW-HTSM Grant (No. 12789) and the NWO Vrije Programma (TNW18.071).

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